BLF7G10L-250; BLF7G10LS-250

Power LDMOS transistor

Rev. 1 — 25 February 2011

Objective data sheet

1. Product profile

1.1 General description

250 W LDMOS power transistor for base station applications at frequencies from 920 MHz to 960 MHz.

Table 1. Typical performance

Typical RF performance at $T_{\rm case}$ = 25 °C in a common source class-AB production test circuit.

Mode of operation	f	I _{Dq}	V _{DS}	P _{L(AV)}	Gp	$\eta_{\mathbf{D}}$	ACPR
	(MHz)	(mA)	(V)	(W)	(dB)	(%)	(dBc)
2-carrier W-CDMA	920 to 960	2000	30	60	19	30	-32 <mark>[1]</mark>

^[1] Test signal: 3GPP; test model 1; 64 DPCH; PAR = 7.5 dB at 0.01 % probability on CCDF per carrier. Carrier spacing 5 MHz.

1.2 Features and benefits

- Excellent ruggedness
- High efficiency
- Low R_{th} providing excellent thermal stability
- Designed for broadband operation (920 MHz to 960 MHz)
- Lower output capacitance for improved performance in Doherty applications
- Designed for low memory effects providing excellent pre-distortability
- Internally matched for ease of use
- Integrated ESD protection
- Compliant to Directive 2002/95/EC, regarding Restriction of Hazardous Substances (RoHS)

1.3 Applications

RF power amplifiers for W-CDMA base stations and multi carrier applications in the 920 MHz to 960 MHz frequency range



2. Pinning information

Table 2. Pinning

Tubic 2.	9		
Pin	Description	Simplified outline	Graphic symbol
BLF7G10L	-250 (SOT502A)		
1	drain		
2	gate	5 3	ا_ر
3	source	[1]	2 —
			3 sym112
			symiiz
BLF/G10L	S-250 (SOT502B)		
1	drain		
2	gate	3	, <u>,</u>
3	source	[1]	2
			3
			sym112

^[1] Connected to flange

3. Ordering information

Table 3. Ordering information

Type number	Packag	Package				
	Name	Description	Version			
BLF7G10L-250	-	flanged LDMOST ceramic package; 2 mounting holes; 2 leads	SOT502A			
BLF7G10LS-250	-	earless flanged LDMOST ceramic package; 2 leads	SOT502B			

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage		-	65	V
V _{GS}	gate-source voltage		-0.5	+13	V
I_D	drain current		-	56	Α
T _{stg}	storage temperature		-65	+150	°C
Tj	junction temperature		-	225	°C

5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Тур	Unit
R _{th(j-c)}	thermal resistance from junction to case	$T_{case} = 80 ^{\circ}C; P_{L} = 60 W;$ $V_{DS} = 30 V; I_{Dq} = 2000 mA$	0.30	K/W

BLF7G10L-250_7G10LS-250

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6. Characteristics

Table 6. Characteristics

 $T_i = 25$ °C unless otherwise specified.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$V_{(BR)DSS}$	drain-source breakdown voltage	$V_{GS} = 0 \text{ V}; I_D = 2.7 \text{ mA}$	-	67	-	V
V _{GS(th)}	gate-source threshold voltage	$V_{DS} = 10 \text{ V}; I_D = 270 \text{ mA}$	-	1.9	-	V
I _{DSS}	drain leakage current	$V_{GS} = 0 \text{ V}; V_{DS} = 28 \text{ V}$	-	-	-	μΑ
I_{DSX}	drain cut-off current	$V_{GS} = V_{GS(th)} + 3.75 \text{ V};$ $V_{DS} = 10 \text{ V}$	-	49	-	Α
I _{GSS}	gate leakage current	$V_{GS} = 11 \text{ V}; V_{DS} = 0 \text{ V}$	-	-	-	nA
9 _{fs}	forward transconductance	$V_{DS} = 10 \text{ V}; I_{D} = 13.5 \text{ A}$	-	19.3	-	S
R _{DS(on)}	drain-source on-state resistance	$V_{GS} = V_{GS(th)} + 3.75 \text{ V};$ $I_D = 9.45 \text{ A}$	-	0.048	-	Ω

7. Test information

Table 7. Functional test information

Mode of operation: 2-carrier W-CDMA; PAR = 7.5 dB at 0.01 % probability on the CCDF; 3GPP test model 1; 64 DPCH; f_1 = 920 MHz; f_2 = 925 MHz; f_3 = 955 MHz; f_4 = 960 MHz; RF performance at V_{DS} = 30 V; I_{Dq} = 2000 mA; T_{case} = 25 °C; unless otherwise specified; in a class-AB production test circuit.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$P_{L(AV)}$	average output power		-	60	-	W
Gp	power gain	$P_{L(AV)} = 60 \text{ W}$	-	19	-	dB
RL_{in}	input return loss	$P_{L(AV)} = 60 \text{ W}$	-	-10	-	dB
η_{D}	drain efficiency	$P_{L(AV)} = 60 \text{ W}$	-	30	-	%
ACPR	adjacent channel power ratio	$P_{L(AV)} = 60 \text{ W}$	-	-32	-	dBc

Table 8. PAR performance

Mode of operation: 1-carrier W-CDMA; PAR = 7.5 dB at 0.01 % probability on the CCDF; 3GPP test model 1; 64 DPCH; f_1 = 960 MHz; RF performance at V_{DS} = 30 V; I_{Dq} = 2000 mA; T_{case} = 25 °C; unless otherwise specified; in a class-AB production test circuit.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
PAR _O	output peak-to-average ratio	$P_{L(AV)}$ = 100 W at 0.01 % probability on CCDF	-	4.6	-	dB

7.1 Ruggedness in class-AB operation

The BLF7G10L-250 and BLF7G10LS-250 are capable of withstanding a load mismatch corresponding to VSWR = 10 : 1 through all phases under the following conditions: $V_{DS} = 30 \text{ V}$; $I_{Dq} = 2000 \text{ mA}$; $P_{L} = 200 \text{ W}$ (CW); f = 920 MHz to 960 MHz.

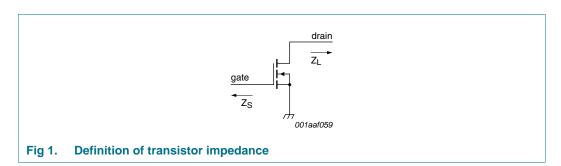
7.2 Impedance information

Table 9. Typical impedance information

 $I_{Dq} = 2000 \text{ mA}$; main transistor $V_{DS} = 30 \text{ V}$.

 $Z_{\rm S}$ and $Z_{\rm L}$ defined in <u>Figure 1</u>.

f (MHz)	Z _S (Ω)	Z _L (Ω)
925	3.46 – j3.57	1.10 – j1.20
942	3.55 – j3.64	0.98 – j1.00
960	3.77 – j4.88	0.92 – j0.96



8. Package outline

Flanged LDMOST ceramic package; 2 mounting holes; 2 leads

SOT502A

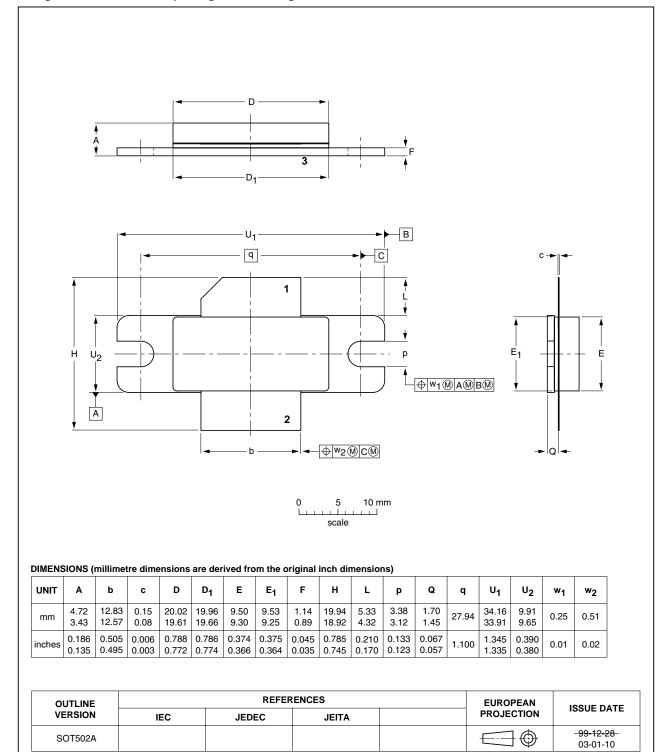


Fig 2. Package outline SOT502A

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Earless flanged LDMOST ceramic package; 2 leads

SOT502B

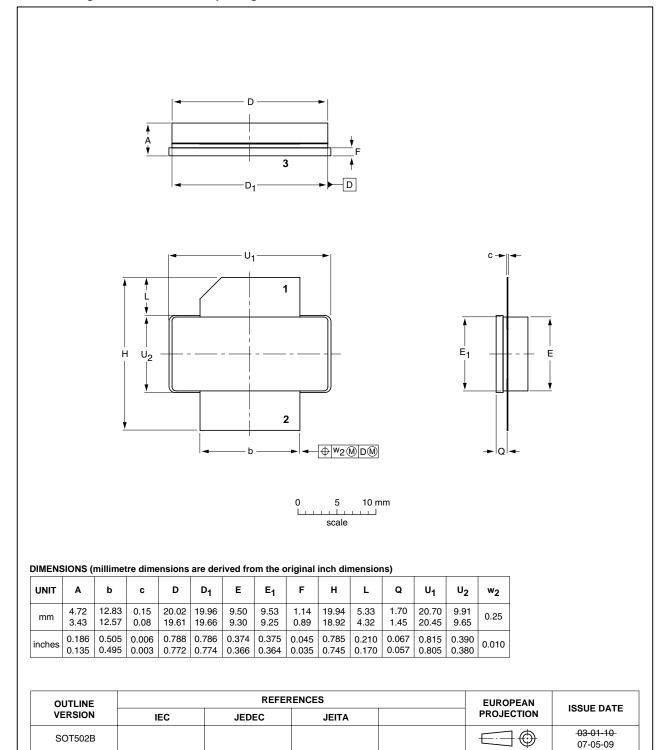


Fig 3. Package outline SOT502B

9. Abbreviations

Table 10. Abbreviations

Acronym	Description
3GPP	Third Generation Partnership Project
CCDF	Complementary Cumulative Distribution Function
CW	Continuous Wave
DPCH	Dedicated Physical CHannel
ESD	ElectroStatic Discharge
LDMOS	Laterally Diffused Metal Oxide Semiconductor
LDMOST	Laterally Diffused Metal Oxide Semiconductor Transistor
PAR	Peak-to-Average power Ratio
RF	Radio Frequency
VSWR	Voltage Standing Wave Ratio
W-CDMA	Wideband Code Division Multiple Access

10. Revision history

Table 11. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
BLF7G10L-250_7G10LS-250 v.1	20110225	Objective data sheet	-	-

11. Legal information

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Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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